

Figure 1. XRD and GIXRD scans of AlN, GaN, and InN on Si and Sapphire substrates

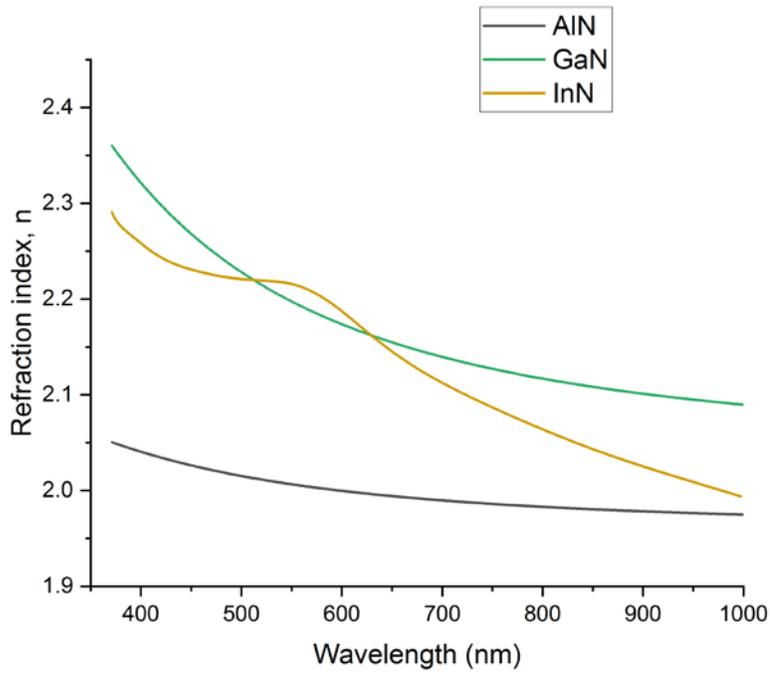


Figure 2. Ex situ spectroscopic ellipsometry measurements of the spectral refractive index for AlN, GaN, and InN on sapphire substrates

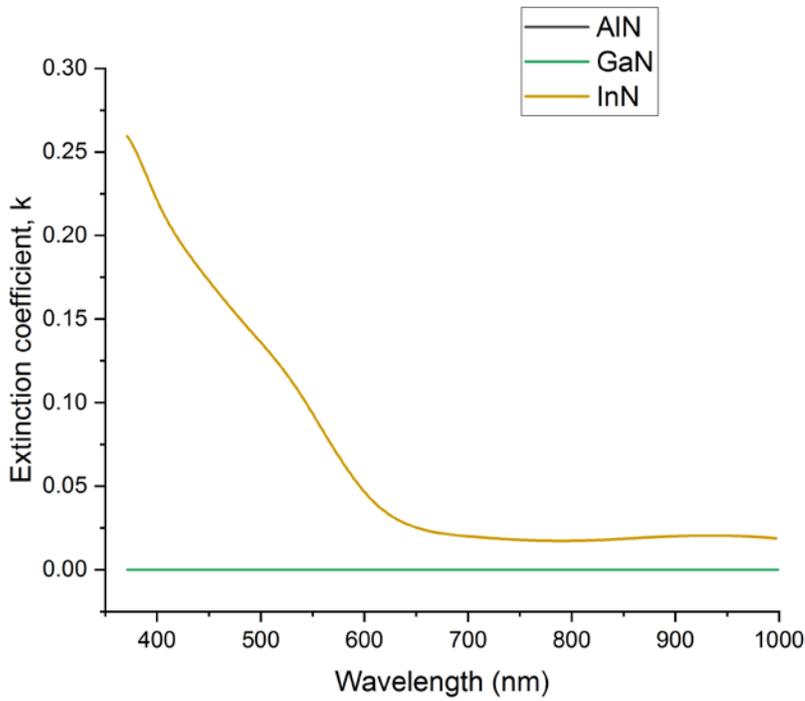


Figure 3. Ex situ spectroscopic ellipsometry measurements of the spectral extinction coefficient for AlN, GaN, and InN on sapphire substrates